# Search Notes



Application/Contro	l No
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10549752

# Examiner

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# Applicant(s)/Patent Under Reexamination

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#### **Art Unit**

2615

### SEARCHED

Class	Subclass	Date	Examiner
391	98-101	2/6/2008	DEF
704	233,267,211,278,500,501,211	2/18/2008	DEF

## **SEARCH NOTES**

Search Notes	Date	Examiner
Assignee/Inventor search	2/6/2008	DEF
word search; combined class/word search	2/6,8,13,14,18/0 8	DEF

### **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner
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